ON Semiconductor

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N-Channel Power MOSFET 600 V, 550 m Ω

Features

- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parame	Symbol	NDD	Unit		
Drain-to-Source Voltage	V_{DSS}	600	V		
Gate-to-Source Voltage			V_{GS}	±25	V
Continuous Drain Current R _{θJC}	Steady State	T _C = 25°C	I _D	8.2	Α
		T _C = 100°C		5.2	
Power Dissipation – $R_{\theta JC}$	Steady State	T _C = 25°C	P _D	94	W
Pulsed Drain Current t _p = 10 μs			I _{DM}	34	Α
Operating Junction and S Temperature	T _J , T _{STG}	-55 to +150	°C		
Source Current (Body Di	Is	8.2	Α		
Single Pulse Drain-to-S Energy (I _D = 4 A)	EAS	54	mJ		
Peak Diode Recovery (N	dv/dt	15	V/ns		
Lead Temperature for So	T_L	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. I_{SD} < 8.2 A, $di/dt \le 400$ A/ μ s, V_{DS} peak $\le V_{(BR)DSS}$, V_{DD} = 80% $V_{(BR)DSS}$

THERMAL RESISTANCE

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) NDD60N550U1	$R_{\theta JC}$	1.3	°C/W
Junction-to-Ambient Steady State (Note 3) NDD60N550U1 (Note 2) NDD60N550U1-1 (Note 2) NDD60N550U1-35	$R_{ hetaJA}$	47 98 95	°C/W

- 2. Insertion mounted
- 3. Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces)

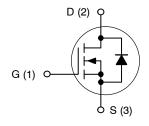


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX		
600 V	550 m Ω @ 10 V		

N-Channel MOSFET







 IPAK
 DPAK

 CASE 369D
 CASE 369C

 STYLE 2
 STYLE 2



IPAK CASE 369AD STYLE 2

MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information on page 3 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Characteristic	Symbol	Test Conditions	s	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V, } I_{D} = 1 \text{ mA}$		600			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				540		mV/°C
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	T _J = 25°C			1	μΑ
			T _J = 125°C			100	1
Gate-to-Source Leakage Current	I _{GSS}	V _{GS} = ±25 V	•			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250$	Ο μΑ	2	3.2	4	٧
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	Reference to 25°C, I _D =	: 250 μA		7.6		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 4$	ł A		510	550	mΩ
Forward Transconductance	9FS	$V_{DS} = 15 \text{ V}, I_D = 4$	A		7.0		S
DYNAMIC CHARACTERISTICS							
Input Capacitance	C _{iss}				540		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f$	= 1 MHz		33		1
Reverse Transfer Capacitance	C _{rss}				1.6		1
Effective output capacitance, energy related (Note 6)	C _{o(er)}	V _{GS} = 0 V, V _{DS} = 0 to 480 V			24		
Effective output capacitance, time related (Note 7)	C _{o(tr)}	I_D = constant, V_{GS} = 0 V, V_{DS} = 0 to 480 V			84		
Total Gate Charge	Q_g	V _{DS} = 300 V, I _D = 9.5 A, V _{GS} = 10 V			18		nC
Gate-to-Source Charge	Q_{gs}				3.4		1
Gate-to-Drain Charge	Q _{gd}				8.7		1
Plateau Voltage	V_{GP}				5.4		V
Gate Resistance	R_{g}				5.5		Ω
RESISTIVE SWITCHING CHARACTER	ISTICS (Note 5))				•	
Turn-on Delay Time	t _{d(on)}				8		ns
Rise Time	t _r	V _{DD} = 300 V, I _D = 9.5 A,			14		
Turn-off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, R_G = 0$	ο Ω΄		20		
Fall Time	t _f				17		1
SOURCE-DRAIN DIODE CHARACTER					-	-	-
Diode Forward Voltage	V_{SD}	$I_S = 8.2 \text{ A}, V_{GS} = 0 \text{ V}$ $T_J = 25^{\circ}\text{C}$ $T_J = 100^{\circ}\text{C}$			0.9	1.3	V
					0.82		1
Reverse Recovery Time	t _{rr}	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 9.5 \text{ A}, d_{i}/d_{t} = 100 \text{ A}/\mu\text{s}$			290		ns
Charge Time	ta				160		1
Discharge Time	t _b				130		1
Reverse Recovery Charge	Q _{rr}				2.6	<u> </u>	μС

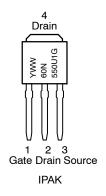
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

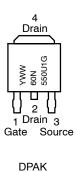
4. Pulse Width $\leq 300~\mu$ s, Duty Cycle $\leq 2\%$.

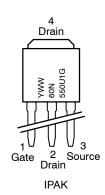
5. Switching characteristics are independent of operating junction temperatures.

6. $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$ 7. $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

MARKING DIAGRAMS







Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NDD60N550U1-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N550U1-35G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N550U1T4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL CHARACTERISTICS

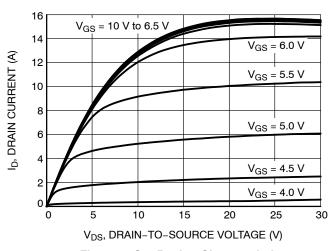


Figure 1. On-Region Characteristics

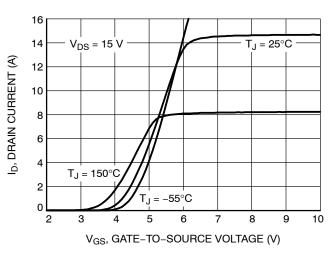


Figure 2. Transfer Characteristics

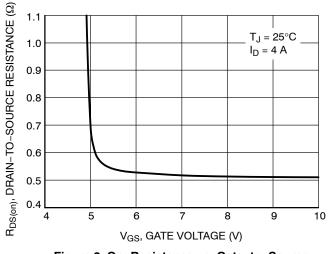


Figure 3. On-Resistance vs. Gate-to-Source Voltage

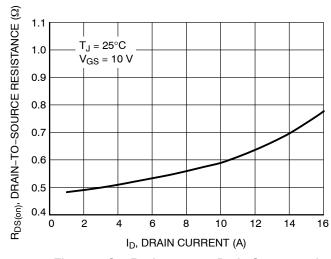


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

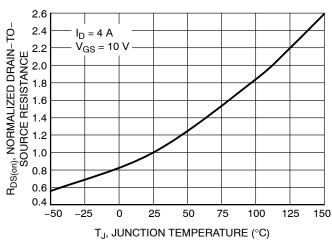


Figure 5. On–Resistance Variation with Temperature

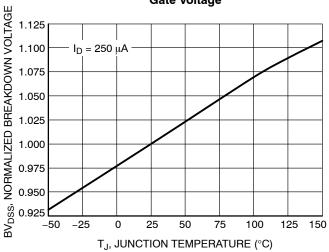


Figure 6. Breakdown Voltage Variation with Temperature

TYPICAL CHARACTERISTICS

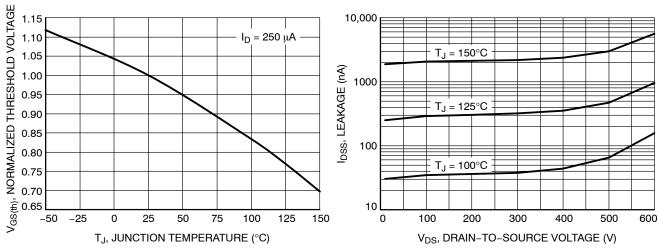


Figure 7. Threshold Voltage Variation with Temperature

Figure 8. Drain-to-Source Leakage Current vs. Voltage

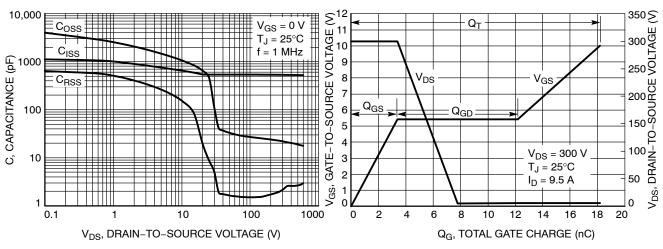


Figure 9. Capacitance Variation

Figure 10. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

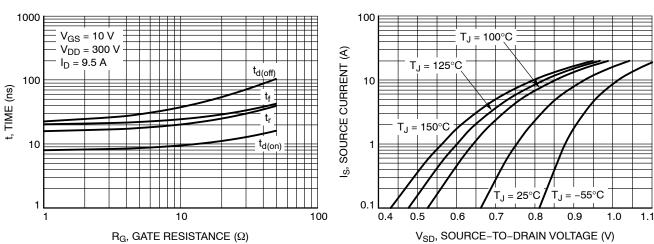


Figure 11. Resistive Switching Time Variation vs. Gate Resistance

Figure 12. Diode Forward Voltage vs. Current

TYPICAL CHARACTERISTICS

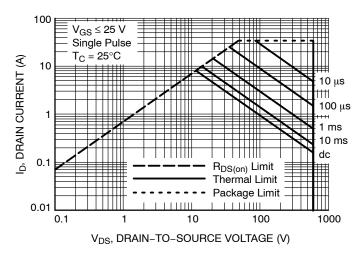


Figure 13. Maximum Rated Forward Biased Safe Operating Area

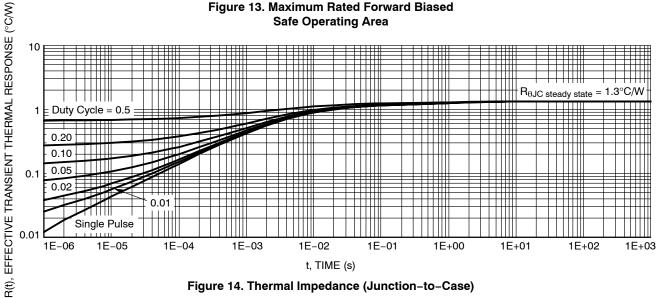
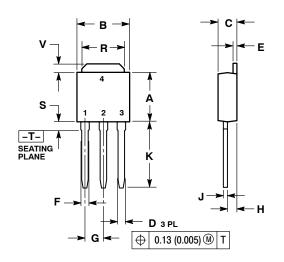
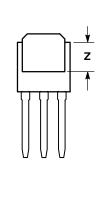


Figure 14. Thermal Impedance (Junction-to-Case)

PACKAGE DIMENSIONS

IPAK CASE 369D ISSUE C





- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
Κ	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

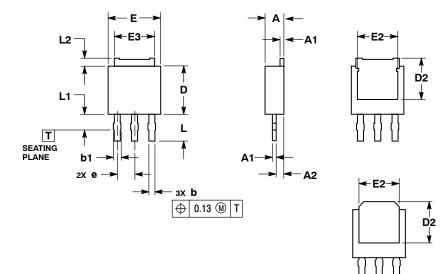
STYLE 2:

PIN 1. GATE 2. DRAIN

- 3. SOURCE
- 4. DRAIN

3.5 MM IPAK, STRAIGHT LEAD

CASE 369AD **ISSUE B**



- NOTES:

 1.. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2.. CONTROLLING DIMENSION: MILLIMETERS.

 3. DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS				
DIM	MIN	MAX			
Α	2.19	2.38			
A1	0.46	0.60			
A2	0.87	1.10			
b	0.69	0.89			
b1	0.77	1.10			
D	5.97	6.22			
D2	4.80				
E	6.35	6.73			
E2	4.57	5.45			
E3	4.45	5.46			
е	2.28	2.28 BSC			
L	3.40	3.60			
L1	-	2.10			
L2	0.89	1.27			

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

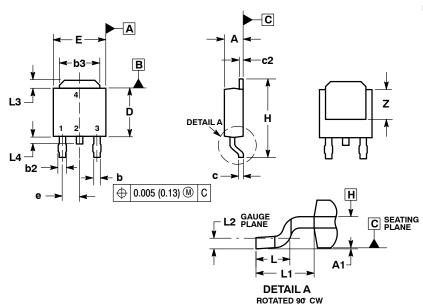
- 4. DRAIN

OPTIONAL CONSTRUCTION

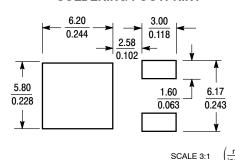
PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE)

CASE 369C ISSUE D



SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14 5M 1994
- 2. CONTROLLING DIMENSION: INCHES.
- 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- 4. DIMENSIONS DAND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIM	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74	REF	
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2:

- PIN 1. GATE 2. DRAIN 3. SOURCE
 - 4. DRAIN

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